

# **Device Modeling Report**

COMPONENTS:THYRISTOR  
PART NUMBER:BT151U-800C  
MANUFACTURER: PHILIPS SEMICONDUCTOR



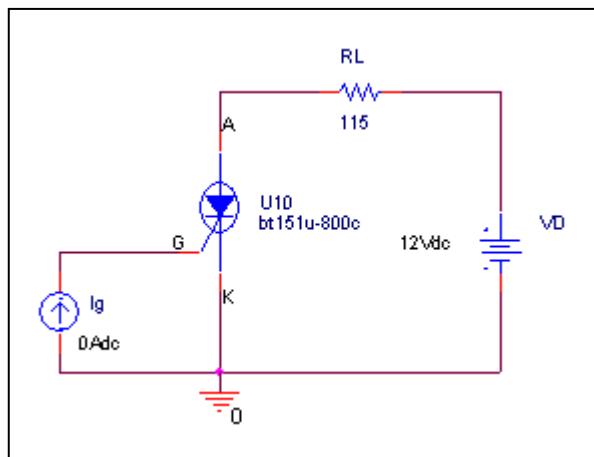
**Bee Technologies Inc.**

## DIODE MODEL

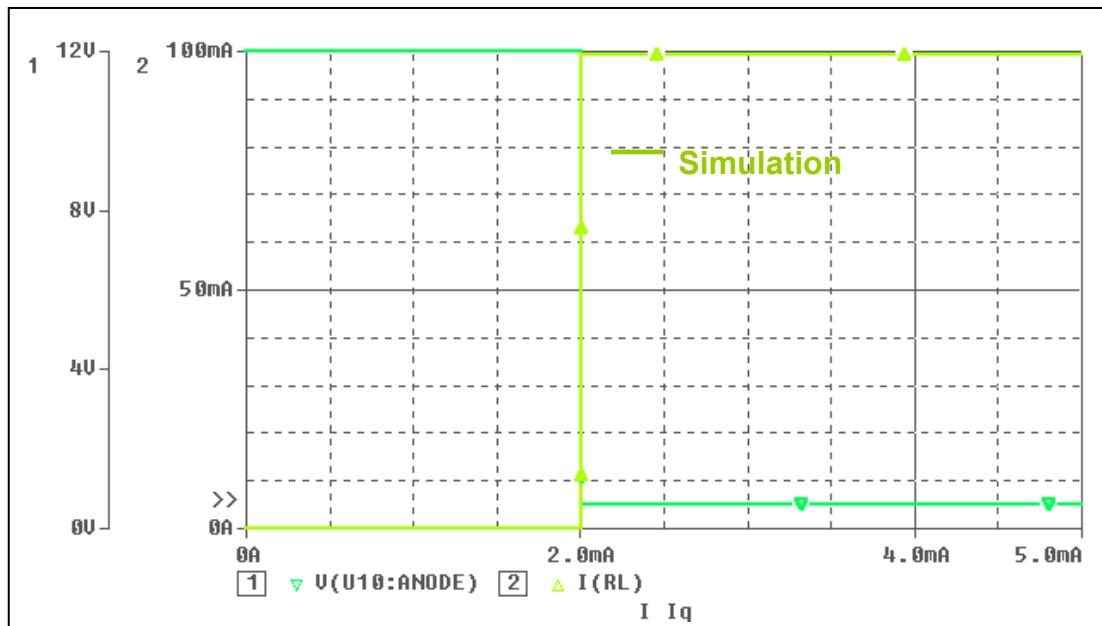
Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## IG-VT Characteristic

Evaluation Circuit



Simulation result

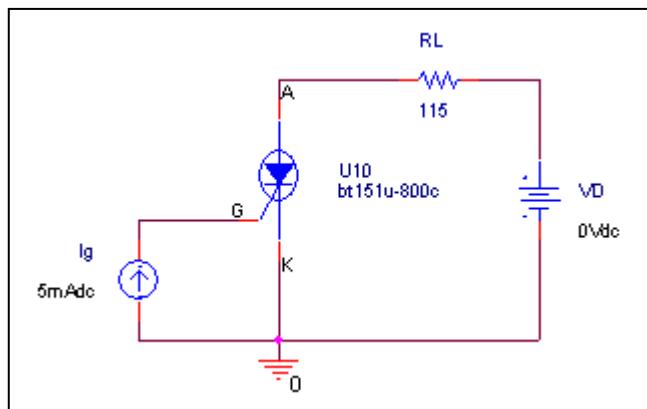


Comparison Table

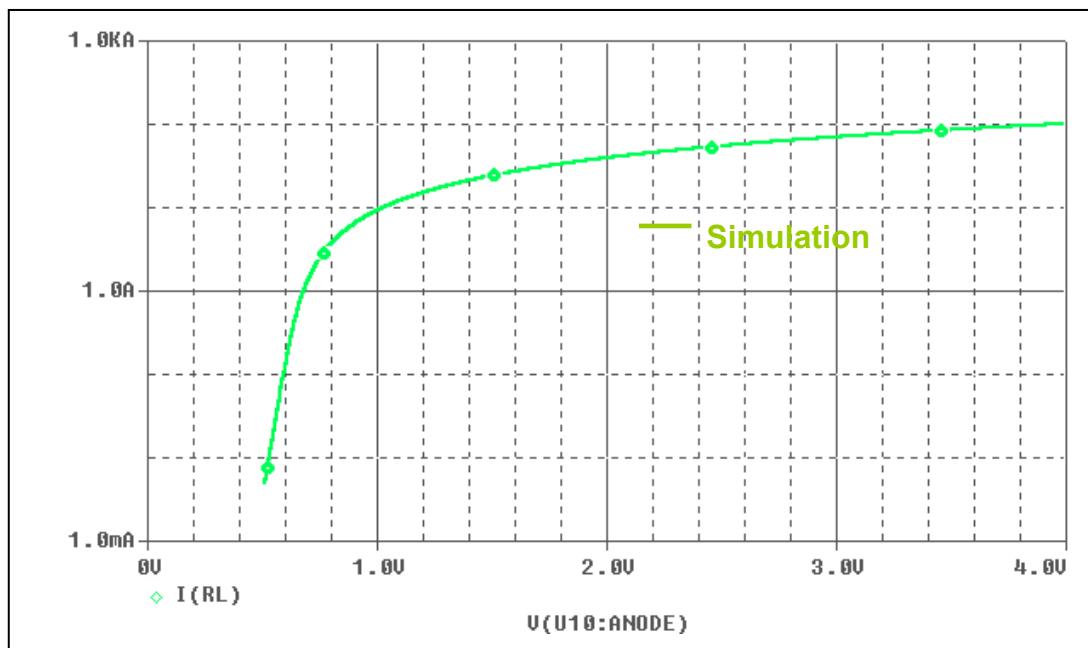
	Measurement	Simulation	% Error
$I_{G_T}$ (mA)	2	2	0
$V_{G_T}$ (V)	0.6	0.592672	-1.22133

## ITM-VM Characteristic

Evaluation Circuit



Simulation result

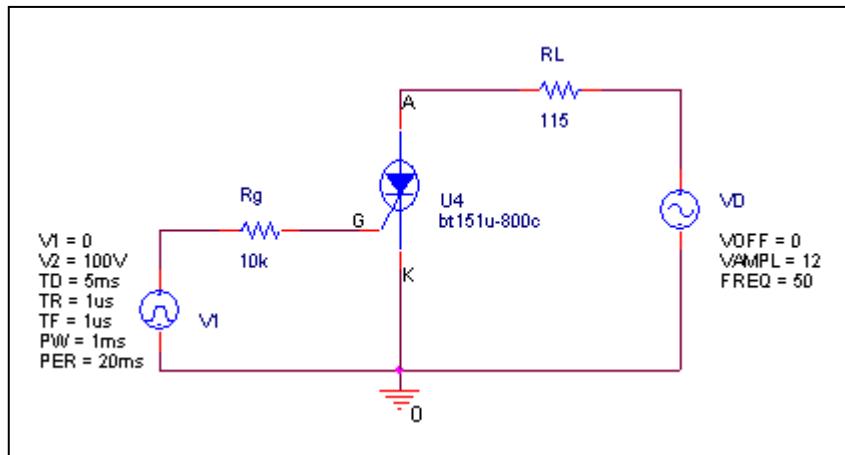


Comparison Table

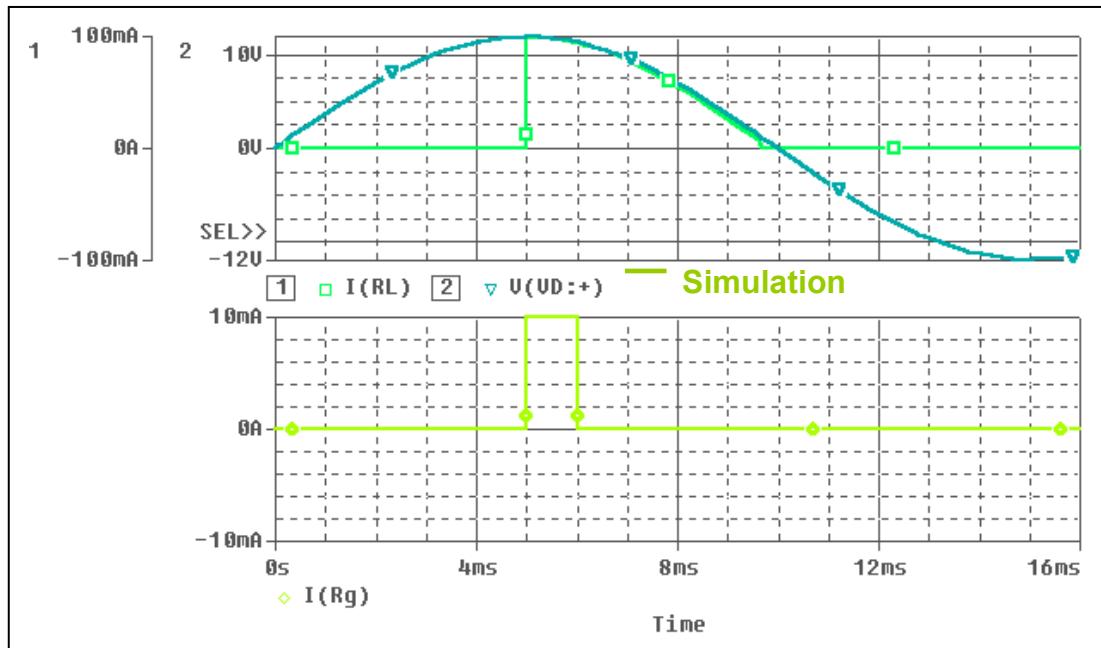
At ITM=23A	Measurement	Simulation	% Error
VTM(V)	1.44	1.4714	2.18056

## Holding Characteristic (IH)

Evaluation Circuit



Simulation result

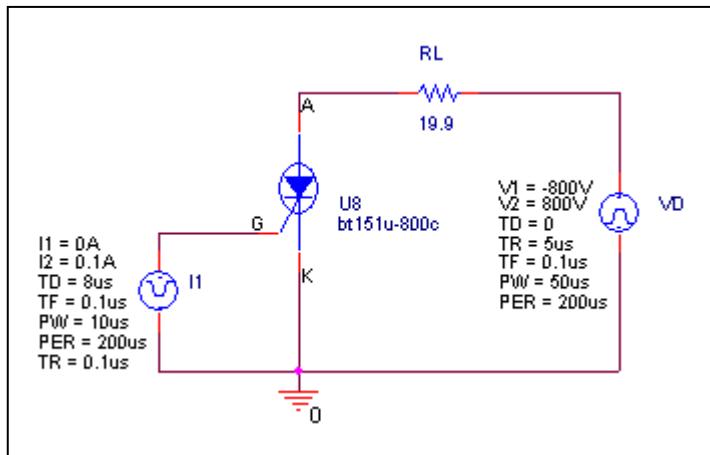


Comparison Table

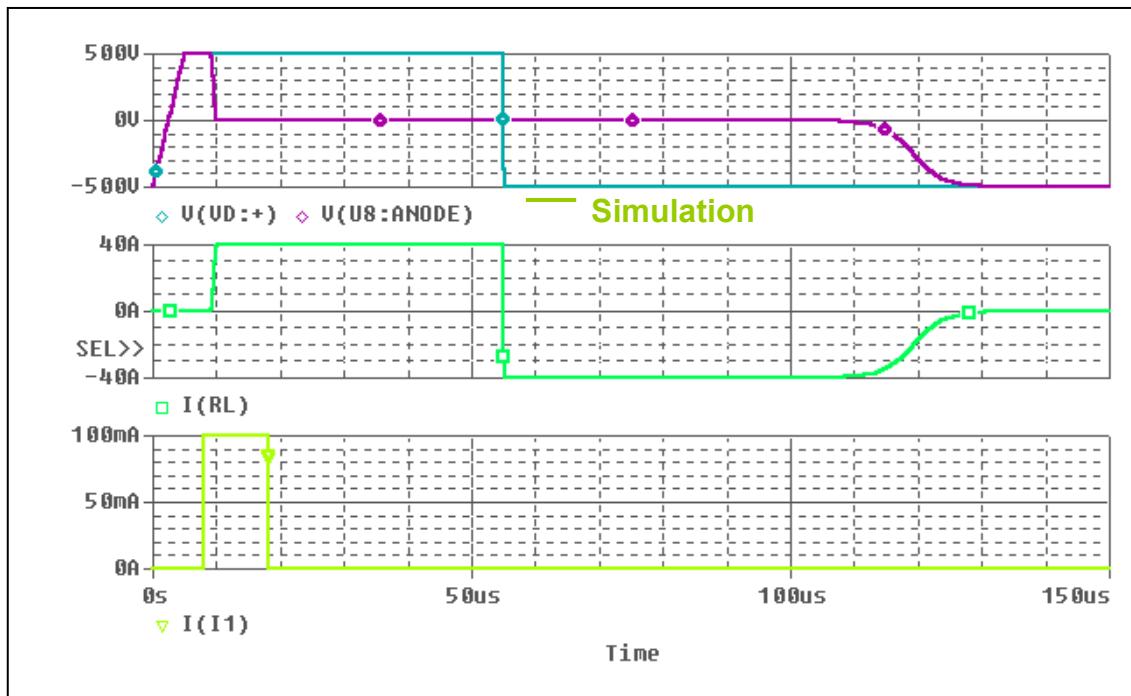
$VD=12V$	Measurement	Simulation	% Error
$I_H(mA)$	7	6.7430	-3.6714

## Switching Time Characteristic

Evaluation Circuit



Simulation result



Comparison Table

	Measurement	Simulation	%Error
$T_{on}(\mu s)$	2	2.0861	4.3050
$T_{off}(\mu s)$	70	69.441	-0.7986